

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

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| In re Application |) | <u>PATENT APPLICATION</u> |
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| Inventors: Frederick Ware, et al. |) | |
| |) | |
| Application No.: 10/768,443 |) | Art Unit: 2829 |
| |) | |
| Filed Date: Jan. 30, 2004 |) | Examiner: Nguyen, T. |
| |) | |
| Title: METHOD AND APPARATUS FOR TEST |) | Customer No.: 38456 |
| CHARACTERIZATION OF SEMICONDUCTOR |) | |
| COMPONENTS |) | |
| |) | |

RESPONSE TO OFFICE ACTION UNDER 37 C.F.R. §1.111

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

This RESPONSE is in reply to the outstanding Office action.

AMENDMENTS to the CLAIMS begin on Page 2 of this RESPONSE.

REMARKS begin on Page 28 of this RESPONSE.